







SN54HC112, SN74HC112

SCLS099H - DECEMBER 1982 - REVISED JUNE 2022

# SNx4HC112 Dual J-K Negative-Edge-Triggered Flip-Flops With Clear and Preset

#### 1 Features

- Wide operating voltage range of 2 V to 6 V
- Outputs can drive up to 10 LSTTL loads
- Low power consumption, 40-µA max I<sub>CC</sub>
- Typical  $t_{pd}$  = 13 ns
- ±4-mA output drive at 5 V
- Low input current of 1 µA max

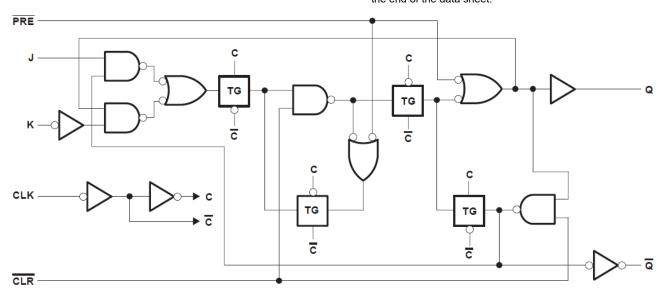
#### 2 Description

The 'HC112 devices contain two independent J-K negative-edge-triggered flip-flops. A low level at the preset (PRE) or clear (CLR) inputs sets or resets the outputs, regardless of the levels of the other inputs. When PRE and CLR are inactive (high), data at the J and K inputs meeting the setup time requirements are transferred to the outputs on the negative-going edge of the clock (CLK) pulse. Clock triggering occurs at a voltage level and is not directly related to the fall time of the CLK pulse. Following the hold-time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. These versatile flipflops perform as toggle flip-flops by tying J and K high.

#### **Device Information**

PART NUMBER	PACKAGE <sup>(1)</sup>	BODY SIZE (NOM)
SN54HC112J	CDIP (16)	24.38 mm × 6.92 mm
SN74HC112D	SOIC (16)	9.90 mm × 3.90 mm
SN74HC112N	PDIP (16)	19.31 mm × 6.35 mm
SN54HC112FK	LCCC (20)	8.89 mm × 8.45 mm
SN54HC112W	CFP (16)	10.16 mm × 6.73 mm

For all available packages, see the orderable addendum at the end of the data sheet.



**Functional Block Diagram** 



**Page** 

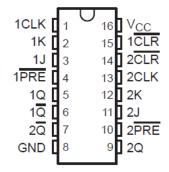
## **Table of Contents**

1 Features	1	7.1 Overview	
2 Description		7.2 Functional Block Diagram	
3 Revision History	<u>2</u>	7.3 Device Functional Modes	
4 Pin Configuration and Functions	3	8 Power Supply Recommendations	10
5 Specifications	4	9 Layout	10
5.1 Absolute Maximum Ratings	4	9.1 Layout Guidelines	10
5.2 Recommended Operating Conditions <sup>(2)</sup>	4	10 Device and Documentation Support	1
5.3 Thermal Information	4	10.1 Receiving Notification of Documentation Up	odates 1
5.4 Electrical Characteristics	6	10.2 Support Resources	<u>1</u> '
5.5 Timing Requirements	6	10.3 Trademarks	11
5.6 Switching Characteristics	7	10.4 Electrostatic Discharge Caution	1 <sup>*</sup>
5.7 Operating Characteristics	7	10.5 Glossary	
6 Parameter Measurement Information	8	11 Mechanical, Packaging, and Orderable	
7 Detailed Description	9	Information	<u>1</u> '
3 Revision History NOTE: Page numbers for previous revisions	•	, 3	
Changes from Revision G (February 2022	) to Revisio	n H (June 2022)	Page
Junction-to-ambient thermal resistance value	alues increas	sed. D was 73 is now 117.2, N was 67 is now 89	9.1 <mark>₄</mark>

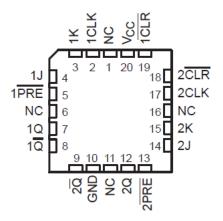
Changes from Revision F (September 2003) to Revision G (February 2022)



# **4 Pin Configuration and Functions**



J, D, N, W package 16-Pin CDIP, SOIC, PDIP, CFP Top View



NC - No internal connection

FK Package 20-Pin LCCC Top View



## **5 Specifications**

#### 5.1 Absolute Maximum Ratings

over operating free-air temperature range<sup>(1)</sup>

			MIN	MAX	UNIT
V <sub>CC</sub>	Supply voltage range	-0.5	7	mA	
I <sub>IK</sub>	Input clamp current <sup>(2)</sup>		±20	mA	
I <sub>OK</sub>	Output clamp current <sup>(2)</sup>	$V_O < 0$ or $V_O > V_{CC}$		±20	mA
Io	Continuous output current	$V_O = 0$ to $V_{CC}$		±25	mA
	Continuous current through V <sub>CC</sub> or GND			±50	mA
TJ	Junction temperature		150	°C	
T <sub>stg</sub>	Storage temperature range		-65	150	°C

<sup>1)</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

## 5.2 Recommended Operating Conditions(2)

			SN	54HC112		SN	74HC112		UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNII	
V <sub>CC</sub>	Supply voltage		2	5	6	2	5	6	V	
	High-level input voltage	V <sub>CC</sub> = 2 V	1.5			1.5				
V <sub>IH</sub>		V <sub>CC</sub> = 4.5 V	3.15			3.15			V	
		V <sub>CC</sub> = 6 V	4.2			4.2				
	Low-level input voltage	V <sub>CC</sub> = 2 V			0.5			0.5		
V <sub>IL</sub>		V <sub>CC</sub> = 4.5 V			1.35			1.35	V	
		V <sub>CC</sub> = 6 V			1.8			1.8		
VI	Input voltage		0		V <sub>CC</sub>	0		V <sub>CC</sub>	V	
Vo	Output voltage		0		V <sub>CC</sub>	0		V <sub>CC</sub>	V	
		V <sub>CC</sub> = 2 V			1000			1000		
t <sub>t</sub> (1)	Input transition (rise and fall) time	V <sub>CC</sub> = 4.5 V			500			500	ns	
		V <sub>CC</sub> = 6 V			400			400		
T <sub>A</sub>	Operating free-air temperature		-55		125	-40		85	°C	

<sup>(1)</sup> If this device is used in the threshold region (from V<sub>IL</sub>max = 0.5 V to V<sub>IH</sub>min = 1.5 V), there is a potential to go into the wrong state from induced grounding, causing double clocking. Operating with the inputs at t<sub>t</sub> = 1000 ns and V<sub>CC</sub> = 2 V does not damage the device; however, functionally, the CLK inputs are not ensured while in the shift, count, or toggle operating modes.

## 5.3 Thermal Information

		D (SOIC)	N (PDIP)	
THERMAL METI	RIC	16 PINS	16 PINS	UNIT
$R_{\theta JA}$	Junction-to-ambient thermal resistance <sup>(1)</sup>	117.2	89.1	°C/W
R <sub>θJC(top)</sub>	Junction-to-case (top) thermal resistance	77.2	46.9	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	75.6	47.4	°C/W
Ψлт	Junction-to-top characterization parameter	38.1	11.8	°C/W
ΨЈВ	Junction-to-board characterization parameter	75.3	47	°C/W

Submit Document Feedback

Copyright © 2022 Texas Instruments Incorporated

<sup>(2)</sup> All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



5.3 Thermal Information (continued)

		D (SOIC)	N (PDIP)	
THERMAL METRI	С	16 PINS	16 PINS	UNIT
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	N/A	N/A	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC package thermal metrics application report.



#### **5.4 Electrical Characteristics**

over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		V	T,	<sub>A</sub> = 25°C		SN54H0	C112	SN74HC	112	UNIT
PARAMETER	1231 00	NDITIONS	V <sub>cc</sub>	MIN	TYP	MAX	MIN	MAX	MIN	MAX	0
			2 V	1.9	1.998		1.9		1.9		
V <sub>OH</sub>		I <sub>OH</sub> = -20 μA	4.5 V	4.4	4.499		4.4		4.4		
	$V_I = V_{IH}$ or $V_{IL}$		6 V	5.9	5.999		5.9		5.9		V
		I <sub>OH</sub> = -4 mA	4.5 V	3.98	4.3			3.7		3.84	
		I <sub>OH</sub> = −5.2 mA	6 V	5.48	5.8			5.2		5.34	
			2 V		0.002	0.1		0.1		0.1	
		I <sub>OL</sub> = 20 μA	4.5 V		0.001	0.1		0.1		0.1	
V <sub>OL</sub>	$V_I = V_{IH}$ or $V_{IL}$		6 V		0.001	0.1		0.1		0.1	V
		I <sub>OL</sub> = 4 mA	4.5 V		0.17	0.26		0.4		0.33	
		I <sub>OL</sub> = 5.2 mA	6 V		0.15	0.26		0.4		0.33	
I <sub>I</sub>	V <sub>I</sub> = V <sub>CC</sub> or 0		6 V		±0.1	±100		±1000		±1000	nA
I <sub>CC</sub>	$V_I = V_{CC} \text{ or } 0,  I_O = 0$		6 V			4		80		40	μΑ
C <sub>i</sub>			2 V to 6 V		3	10		10		10	pF

# 5.5 Timing Requirements

over recommended operating free-air temperature range (unless otherwise noted)

				T <sub>A</sub> = 2		SN54H0	C112	SN74H0	C112	LINIT
			V <sub>CC</sub>	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V		5		3.4		4	
f <sub>clock</sub>	Clock frequency	4.5 V		25		17		20	MHz	
		6 V		29		20		24		
			2 V	100		150		125		
		PRE or CLR low	4.5 V	20		30		25		
	Pulse duration		6 V	17		25		21		-
t <sub>w</sub>	Pulse duration		2 V	100		150		125		ns
		CLK high or low	4.5 V	20		30		25		
			6 V	17		25		21		
			2 V	100		150		125		
		Data (J, K)	4.5 V	20		30		25		
	Setup time before CLK↓		6 V	17		25		21		20
t <sub>su</sub>	Setup time before CLK		2 V	100		150		125		ns
		PRE or CLR inactive	4.5 V	20		30		25		
			6 V	17		25		21		
		•	2 V	0		0		0		
t <sub>h</sub>	h Hold time, data after CLK↓		4.5 V	0		0		0		ns
			6 V	0		0		0		



# **5.6 Switching Characteristics**

over recommended operating free-air temperature range,  $C_L$  = 50 pF (unless otherwise noted) (see Parameter Measurement Information)

PARAMETER	FROM	то	V	TA	= 25°C		SN54H0	C112	SN74HC	112	UNIT							
PARAMETER	(INPUT)	(OUTPUT)	V <sub>cc</sub>	MIN	TYP	MAX	MIN	MAX	MIN	MAX	Oitii							
			2 V	5	10		3.4		4									
f <sub>max</sub>			4.5 V	25	50		17		20		MHz							
			6 V	29	60		20		24									
Ī	PRE or CLR			2 V		54	165		245		205							
		$Q$ or $\overline{Q}$	4.5 V		16	33		49		41								
			6 V		13	28		42		35	ns							
t <sub>pd</sub>			2 V		56	125		185		155	115							
	CLK	${\sf Q}$ or $\overline{\sf Q}$	4.5 V		16	25		37		31	_							
			6 V		13	21		31		26								
					2 V		29	75		110		95						
t <sub>t</sub>		Q or $\overline{Q}$	4.5 V		9	15		22		19	ns							
									<u> </u>	6 V		8	13		19		16	

# **5.7 Operating Characteristics**

T<sub>A</sub> = 25°C

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance	No load	35	pF



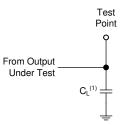
 $V_{CC}$ 

#### **6 Parameter Measurement Information**

Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_t < 6 \text{ ns}$ .

For clock inputs,  $f_{max}$  is measured when the input duty cycle is 50%.

The outputs are measured one at a time with one input transition per measurement.



(1)  $C_L$  includes probe and test-fixture capacitance.

Figure 6-1. Load Circuit for Push-Pull Outputs

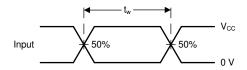


Figure 6-2. Voltage Waveforms, Standard CMOS Inputs Pulse Duration

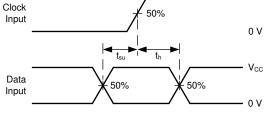


Figure 6-3. Voltage Waveforms, Standard CMOS Inputs Setup and Hold Times

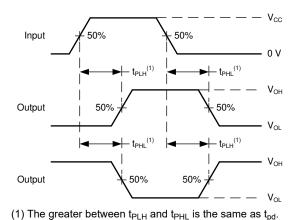
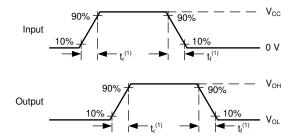


Figure 6-4. Voltage Waveforms, Propagation Delays for Standard CMOS Inputs



(1) The greater between  $t_{\rm r}$  and  $t_{\rm f}$  is the same as  $t_{\rm t}$ .

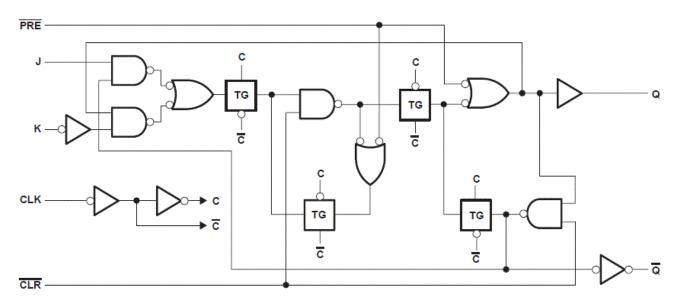
Figure 6-5. Voltage Waveforms, Input and Output Transition Times for Standard CMOS Inputs

#### 7 Detailed Description

#### 7.1 Overview

The 'HC112 devices contain two independent J-K negative-edge-triggered flip-flops. A low level at the preset  $(\overline{PRE})$  or clear  $(\overline{CLR})$  inputs sets or resets the outputs, regardless of the levels of the other inputs. When  $\overline{PRE}$  and  $\overline{CLR}$  are inactive (high), data at the J and K inputs meeting the setup time requirements are transferred to the outputs on the negative-going edge of the clock (CLK) pulse. Clock triggering occurs at a voltage level and is not directly related to the fall time of the CLK pulse. Following the hold-time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. These versatile flip-flops perform as toggle flip-flops by tying J and K high.

## 7.2 Functional Block Diagram



#### 7.3 Device Functional Modes

Table 7-1. Function Table

		INPUTS			OUTI	PUTS	
PRE	CLR	CLK	J	K	Q	Q	
L	Н	X	X	Х	Н	Н	
Н	L	Х	Х	Х	L	Н	
L	L	Х	Х	Х	H <sup>(1)</sup>	H <sup>(1)</sup>	
Н	Н	<b>\</b>	L	L	$Q_0$	$\overline{Q}_0$	
Н	Н	<b>1</b>	Н	L	Н	L	
Н	Н	<b>↓</b>	L	Н	L	Н	
Н	Н	<b>\</b>	Н	Н	Toggle		
Н	Н	Н	Х	Х	$Q_0$	$\overline{Q}_0$	

(1) This configuration is nonstable; that is, it does not persist when either PRE or CLR returns to its inactive (high) level.



#### 8 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the *Recommended Operating Conditions*. Each  $V_{CC}$  terminal should have a good bypass capacitor to prevent power disturbance. A 0.1- $\mu$ F capacitor is recommended for this device. It is acceptable to parallel multiple bypass caps to reject different frequencies of noise. The 0.1- $\mu$ F and 1- $\mu$ F capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

#### 9 Layout

#### 9.1 Layout Guidelines

When using multiple-input and multiple-channel logic devices inputs must not ever be left floating. In many cases, functions or parts of functions of digital logic devices are unused; for example, when only two inputs of a triple-input AND gate are used or only 3 of the 4 buffer gates are used. Such unused input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a logic high or logic low voltage, as defined by the input voltage specifications, to prevent them from floating. The logic level that must be applied to any particular unused input depends on the function of the device. Generally, the inputs are tied to GND or  $V_{CC}$ , whichever makes more sense for the logic function or is more convenient.

#### 10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

#### 10.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

#### 10.2 Support Resources

TI E2E<sup>™</sup> support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

#### 10.3 Trademarks

TI E2E™ is a trademark of Texas Instruments.

All trademarks are the property of their respective owners.

#### 10.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

#### 10.5 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

## 11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

www.ti.com

11-Aug-2022

#### **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
84088012A	ACTIVE	LCCC	FK	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	84088012A SNJ54HC 112FK	Samples
8408801EA	ACTIVE	CDIP	J	16	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	8408801EA SNJ54HC112J	Samples
8408801FA	ACTIVE	CFP	W	16	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	8408801FA SNJ54HC112W	Samples
JM38510/65305BEA	ACTIVE	CDIP	J	16	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	JM38510/ 65305BEA	Samples
M38510/65305BEA	ACTIVE	CDIP	J	16	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	JM38510/ 65305BEA	Samples
SN54HC112J	ACTIVE	CDIP	J	16	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	SN54HC112J	Samples
SN74HC112D	ACTIVE	SOIC	D	16	40	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HC112	Samples
SN74HC112DR	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 85	HC112	Samples
SN74HC112DT	ACTIVE	SOIC	D	16	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	HC112	Samples
SN74HC112N	ACTIVE	PDIP	N	16	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-40 to 85	SN74HC112N	Samples
SNJ54HC112FK	ACTIVE	LCCC	FK	20	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	84088012A SNJ54HC 112FK	Samples
SNJ54HC112J	ACTIVE	CDIP	J	16	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	8408801EA SNJ54HC112J	Samples
SNJ54HC112W	ACTIVE	CFP	W	16	1	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	8408801FA SNJ54HC112W	Samples

<sup>&</sup>lt;sup>(1)</sup> The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

## **PACKAGE OPTION ADDENDUM**

www.ti.com 11-Aug-2022

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

**Important Information and Disclaimer:** The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF SN54HC112, SN74HC112:

Catalog: SN74HC112

Military: SN54HC112

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 5-Oct-2022

#### TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74HC112DR	SOIC	D	16	2500	330.0	16.4	6.6	9.3	2.1	8.0	16.0	Q1
SN74HC112DR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
SN74HC112DR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 5-Oct-2022



#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
SN74HC112DR	SOIC	D	16	2500	366.0	364.0	50.0
SN74HC112DR	SOIC	D	16	2500	356.0	356.0	35.0
SN74HC112DR	SOIC	D	16	2500	340.5	336.1	32.0

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 5-Oct-2022

#### **TUBE**



\*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
84088012A	FK	LCCC	20	1	506.98	12.06	2030	NA
8408801FA	W	CFP	16	1	506.98	26.16	6220	NA
SN74HC112D	D	SOIC	16	40	507	8	3940	4.32
SN74HC112N	N	PDIP	16	25	506	13.97	11230	4.32
SN74HC112N	N	PDIP	16	25	506	13.97	11230	4.32
SNJ54HC112FK	FK	LCCC	20	1	506.98	12.06	2030	NA
SNJ54HC112W	W	CFP	16	1	506.98	26.16	6220	NA

# D (R-PDS0-G16)

## PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



# D (R-PDSO-G16)

# PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



# W (R-GDFP-F16)

# CERAMIC DUAL FLATPACK



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package can be hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only.
- E. Falls within MIL STD 1835 GDFP2-F16



8.89 x 8.89, 1.27 mm pitch

LEADLESS CERAMIC CHIP CARRIER

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



## 14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

# N (R-PDIP-T\*\*)

# PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



#### **IMPORTANT NOTICE AND DISCLAIMER**

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2023, Texas Instruments Incorporated